

<b>Notice of References Cited</b>	Application/Control No. 10/624,224	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Andrew Schechter	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,742,074	04-1998	Takizawa et al.	257/59
	B	US-6,587,160	07-2003	Lee et al.	349/40
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11202353 A	07-1999	Japan	YOSHINO, TAKESHI	G02F 01/1343
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Machine-translation of JP 11-202353.
	V	
	W	
	X	

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